



TS 600 Tensile Stage

The TS 600 Tensile Stage is a completely new, advanced sample stage for in-situ X-ray investigation of stress/strain phenoma in fibres, foils and thin films. The stage can be used in transmission and reflection mode on synchotrons and commercial diffractometers alike.

Gain new insights into the world of strain and stress!

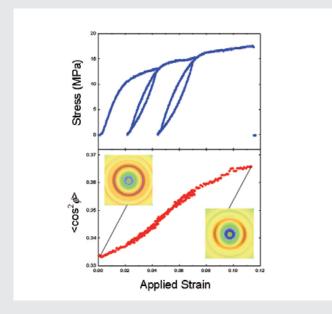
Exploring the world of mechanical properties

With TS 600 Tensile Stage, Anton Paar widens the range of non-ambient sample stages for XRD to the field of in-situ studies of mechanical material properties. TS 600 is the first commercial sample stage designed specifically for in-situ X-ray investigations of structural changes in materials under mechanical load. Because of its compactness and low weight, the instrument can be used on synchotrons as well as on laboratory X-ray diffractometers. And what's more, it can be operated in transmission- and reflection mode.



A strong midget

Despite its small size and low weight, TS 600 can strain samples with a force up to 600 N. Two load cells are available: A low-range, high-resolution one up to 5 N and a full range load cell from 1-600 N. The cells can be easily exchanged and the cell type is automatically detected by the instrument. The force range of 600 N allows investigations on a variety of samples like fibres, foils, thin sheets, etc



Easy access to complex information

TS 600 comes with user-friendly software for stage control and data acquisition. Elongation- and force-controlled straining makes it possible to program complex load profiles, including cyclic straining and creep experiments. The data can be viewed on-line in different representations and exported in various formats.

Features and Benefits

- ▶ Simultaneous straining and X-ray diffraction
- Measurements in transmission- and reflection geometry
- ▶ Large force range with high resolution
- Precise measurement of force and elongation
- ▶ Various sample types like fibres, foils, thin sheets, etc
- Small and light-weight
- ► For synchotrons and commercial X-ray diffractometers
- User-friendly control and data acquisition software

Technical Specifications		
Measuring method	Transmission & Reflection	
Angular range (reflection geometry)	Psi	≤ 20° to 90° (depending on phi)
	Theta	≤ 20° to 90° (depending on phi)
	Phi	0° to ±180°
Force range	5N load cell	0.05 to 5 N
	600N load cell	1 to 600 N
Speed range	0.05 to 5 mm/min	
Displacement resolution	0.	005 mm
Crosshead travel	25 mm	
Sample dimensions	TW	L min 30 mm W max 15 mm T max 2 mm

Dimensions Weight	
Diameter	155 mm
Total height	48.5 mm
Height of sample above base plate	36 mm
Weight	1.3 kg

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Instruments for:

Density & concentration Colloid science

measurement High-precision temperature measurement

Rheometry and viscometry Refractometry
Sample preparation Polarimetry

Microwave synthesis X-ray structure analysis

Specifications subject to change without notice.

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